

Notice of References Cited

Application/Control No.

10/815,398

Applicant(s)/Patent Under
Reexamination
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Examiner

Sin J. Lee

Art Unit

1752

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,280,897 B1	08-2001	Asakawa et al.	430/270.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N	EP 1 085 379 A1	03-2001	European	Douki et al	N/A
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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